

Abstract

5 **TESTING APPARATUS AND METHOD FOR TESTING THE CONTACTING
 BETWEEN A SEMICONDUCTOR DEVICE AND A CARRIER**

10 The invention relates to a testing apparatus, a testing
 system and a testing method, in particular for testing the
 contacting between a semiconductor device and a carrier.
 The invention includes loading of a carrier with a
 semiconductor device, such that the contacting between the
 carrier and the semiconductor device is tested immediately
 after the loading of the carrier with the semiconductor
15 device.